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U.S. PATENT DOCUMENTS

EXAMINER INITIAL			DOCUMENT NUMBER Number-Kind Code (if known)	DATE	NAME	CLASS/ SUBCLASS	FILING DATE
m	b	A1	5,586,041	12/17/1996	Mangrulkar	700/174	
M	10	A2	5,726,920	03/10/1998	Chen et al.	702/108	·
M	10	A3	2002/0055194 A1	05/09/2002	Takanabe	438/4	

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EXAMINER INITIAL		DOCUMENT NUMBER Number-Kind Code (if known)	DATE	COUNTRY	CLASS/ SUBCLASS	TRANSLATION YES OR NO
mls	A4	GB 2 283 116 A	04/26/1995	United Kingdom	-	

EXAMINER INITIAL	OTHER ART – NON PATENT LITERATURE DOCUMENTS (Include name of author, title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date page(s), volume-issue number(s), publisher, city and/or country where published.			
Mb	A5	Copy of European Search Report dated March 10, 2004 for European Patent Application No. 03026035		
mlb	A6	C. Schneider et al., "Automated Photolithography Critical Dimension Controls In A Complex, Mixed Technology, Manufacturing Fab", IBM Microelectronics, 2001 IEEE/SEMI Advanced Semiconductor Manufacturing Conference		

EXAMINER MIL 2 Biles	DATE CONSIDERED 12/16/04

EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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